

#### Is Now Part of



# ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at <a href="https://www.onsemi.com">www.onsemi.com</a>

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA Class 3 medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, emplo



March 2011

# FDT86113LZ

# N-Channel PowerTrench<sup>®</sup> MOSFET 100 V, 3.3 A, 100 m $\Omega$

#### **Features**

- Max  $r_{DS(on)}$  = 100 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 3.3 A
- Max  $r_{DS(on)}$  = 145 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 2.7 A
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability in a widely used surface mount package
- HBM ESD protection level > 3 KV typical (Note 4)
- 100% UIL tested
- RoHS Compliant



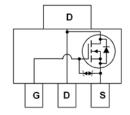
#### **General Description**

This N-Channel logic Level MOSFETs are produced using Fairchild Semiconductor's advanced Power Trench<sup>®</sup> process that has been special tailored to minimize the on-state resistance and yet maintain superior switching performance. G-S zener has been added to enhance ESD voltage level.

#### **Application**

■ DC - DC Switch





#### MOSFET Maximum Ratings T<sub>C</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			100	V	
V <sub>GS</sub>	Gate to Source Voltage			±20	V	
1	Drain Current -Continuous			3.3	^	
ID	-Pulsed			12	A	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	9	mJ	
D	Power Dissipation T	<sub>A</sub> = 25 °C	(Note 1a)	2.2	W	
$P_{D}$	Power Dissipation T	<sub>A</sub> = 25 °C	(Note 1b)	1.0	VV	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Rang	je		-55 to +150	°C	

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	12	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	55	C/VV

### **Package Marking and Ordering Information**

Ĭ	Device Marking	Device	Package	Reel Size	Tape Width	Quantity
Ī	86113LZ	FDT86113LZ	SOT-223	13 "	12 mm	2500 units

## **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		71		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μΑ

#### On Characteristics (Note 2)

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0	1.7	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		-5		mV/°C
	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 3.3 \text{ A}$		75	100	- mΩ
r		$V_{GS} = 4.5 \text{ V}, I_D = 2.7 \text{ A}$		95	145	
r <sub>DS(on)</sub> Static Drain to \$	Static Drain to Source On Nesistance	$V_{GS} = 10 \text{ V}, I_D = 3.3 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		140	189	11152
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_D = 3.3 \text{ A}$		8		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V - 50 V V - 0 V	234	315	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, f = 1 MHz	46	65	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 1411 12	3.1	5	pF

#### **Switching Characteristics**

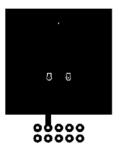
t <sub>d(on)</sub>	Turn-On Delay Time		3.8	10	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 3.3 A,	1.3	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$	10	20	ns
t <sub>f</sub>	Fall Time		1.5	10	ns
$Q_q$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	4.1	6.8	nC
$Q_q$	Total Gate Charge	$V_{GS} = 0 \text{ V to 5 V}$ $V_{DD} = 50 \text{ V},$	2.3	3.9	nC
$Q_{gs}$	Gate to Source Gate Charge	I <sub>D</sub> = 3.3 A	0.68		nC
$Q_{qd}$	Gate to Drain "Miller" Charge		0.85		nC

#### **Drain-Source Diode Characteristics**

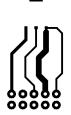
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 3.3 \text{ A}$ (Note 2)	0.86	1.3	V
	Source to Drain Diode 1 of ward voltage	$V_{GS} = 0 V, I_S = 1 A$ (Note 2)	0.77	1.2	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 3.3 A, di/dt = 100 A/μs	31	49	ns
Q <sub>rr</sub>	Reverse Recovery Charge	i <sub>F</sub> = 3.3 A, di/dt = 100 A/μs	21	34	nC

#### Notes:

<sup>1.</sup> R<sub>0JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0JC</sub> is guaranteed by design while R<sub>0JA</sub> is determined by the user's board design.



a) 55 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 118 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3. Starting  $\rm T_J$  = 25°C, L = 0.3 mH,  $\rm I_{AS}$  = 8 A,  $\rm V_{DD}$  = 90 V,  $\rm V_{GS}$  = 10 V.
- 4. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

## Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

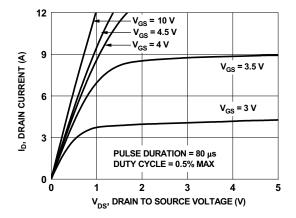


Figure 1. On-Region Characteristics

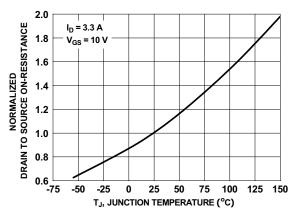


Figure 3. Normalized On-Resistance vs Junction Temperature

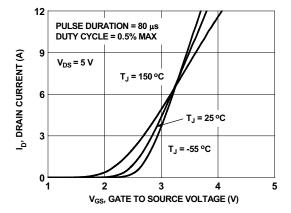


Figure 5. Transfer Characteristics

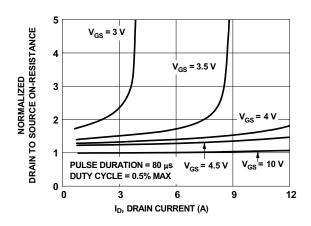


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

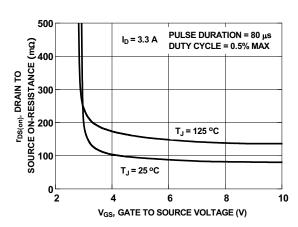


Figure 4. On-Resistance vs Gate to Source Voltage

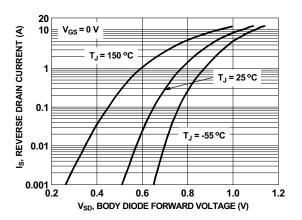


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics $T_J = 25$ °C unless otherwise noted

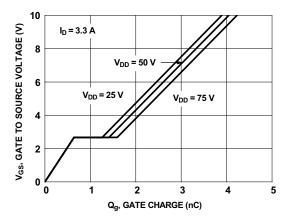
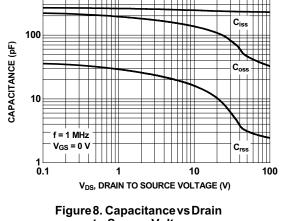


Figure 7. Gate Charge Characteristics



400

to Source Voltage

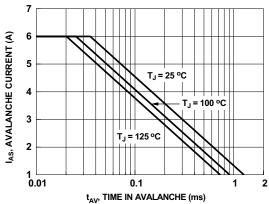


Figure 9. Unclamped Inductive **Switching Capability** 

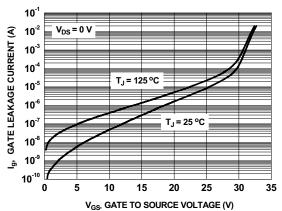


Figure 10. Gate Leakage Current vs Gate to Source Voltage

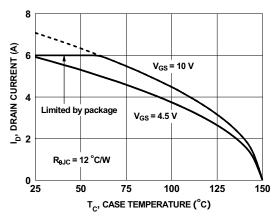


Figure 11. Maximum Continuous Drain **Current vs Case Temperature** 

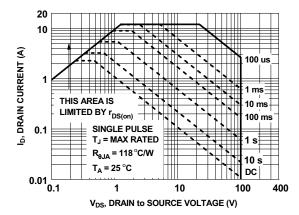


Figure 12. Forward Bias Safe **Operating Area** 



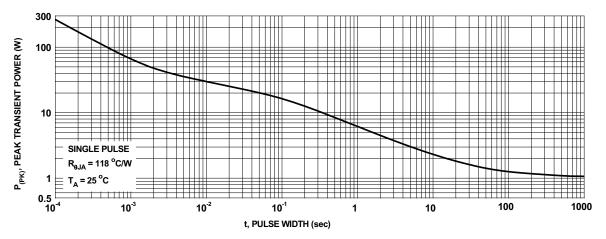


Figure 13. Single Pulse Maximum Power Dissipation

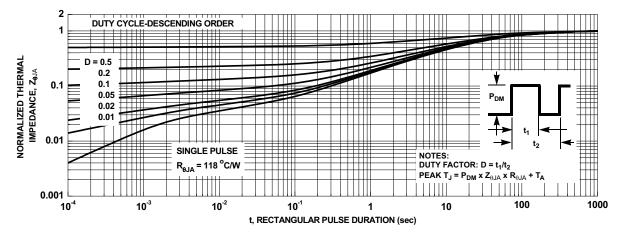
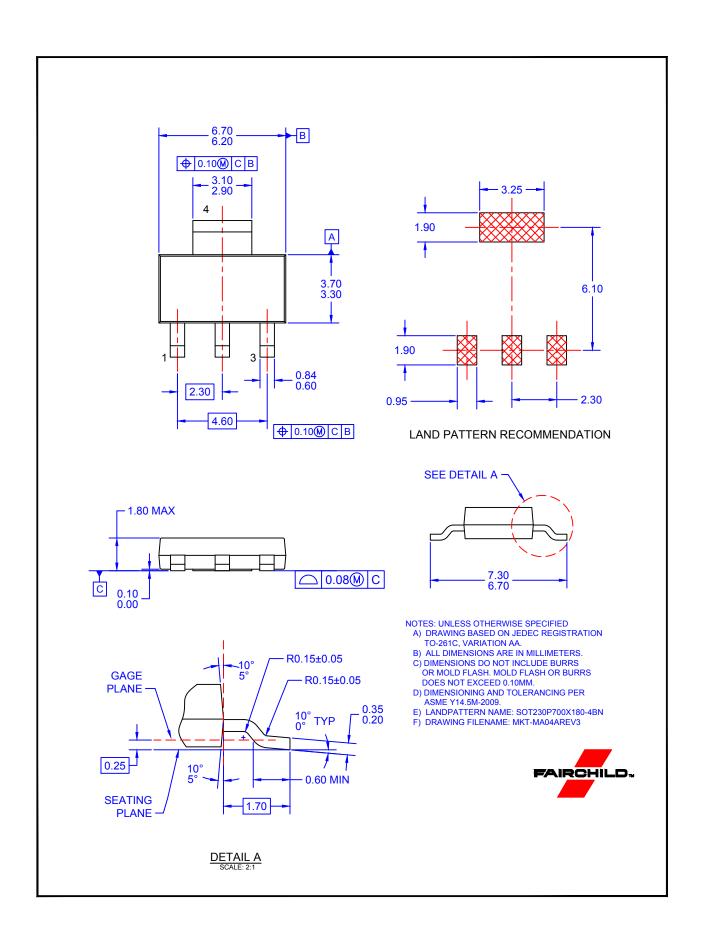


Figure 14. Junction-to-Ambient Transient Thermal Response Curve







#### TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

AccuPower™ F-PFS™ AttitudeEngine™ FRFET®

Global Power Resource<sup>SM</sup> Awinda<sup>®</sup> AX-CAP®\*

GreenBridge™ BitSiC™ Green FPS™ Build it Now™ Green FPS™ e-Series™

CorePLUS™ Gmax™ CorePOWER™  $\mathsf{GTO}^{\mathsf{TM}}$ CROSSVOLT™ IntelliMAX™ CTL™ ISOPLANAR™

Current Transfer Logic™ Making Small Speakers Sound Louder

**DEUXPEED®** and Better™ Dual Cool™ MegaBuck™ EcoSPARK® MIČROCOUPLER™ EfficientMax™ MicroFET™

MicroPak™ MicroPak2™ MillerDrive™ MotionMax™ Fairchild Semiconductor®

MotionGrid® FACT Quiet Series™ MTi<sup>®</sup> FACT<sup>®</sup> MTx® FastvCore™ MVN® FETBench™ mWSaver® FPS™ OptoHiT™ OPTOLOGIC® OPTOPLANAR®

Power Supply WebDesigner™ PowerTrench®

PowerXSTI

Programmable Active Droop™ OFFT

QS™ Quiet Series™ RapidConfigure™

Saving our world, 1mW/W/kW at a time™

SignalWise™ SmartMax™ SMART START™

Solutions for Your Success™

SPM® STEALTH™ SuperFET® SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS® SyncFET™ Sync-Lock™

SYSTEM SYSTEM TinyBoost<sup>®</sup> TinyBuck<sup>®</sup> TinyCalc™ TinyLogic<sup>®</sup> TINYOPTO™

TinvPower™ TinyPWM™ TinyWire™ TranSiC™ TriFault Detect™

TRUECURRENT®\* սSerDes™

UHC Ultra FRFET™

UniFET™ VCX™ VisualMax™ VoltagePlus™ XSTM. Xsens™ 仙童®

**ESBC™** 

**-**®

Fairchild®

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. TO OBTAIN THE LATEST, MOST UP-TO-DATE DATASHEET AND PRODUCT INFORMATION, VISIT OUR <u>AIRCHILDSEMI.COM.</u> FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

Unless otherwise specified in this data sheet, this product is a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability. This product may not be used in the following applications, unless specifically approved in writing by a Fairchild officer: (1) automotive or other transportation, (2) military/aerospace, (3) any safety critical application - including life critical medical equipment - where the failure of the Fairchild product reasonably would be expected to result in personal injury, death or property damage. Customer's use of this product is subject to agreement of this Authorized Use policy. In the event of an unauthorized use of Fairchild's product, Fairchild accepts no liability in the event of product failure. In other respects, this product shall be subject to Fairchild's Worldwide Terms and Conditions of Sale, unless a separate agreement has been signed by both Parties.

#### **ANTI-COUNTERFEITING POLICY**

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com,

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufacturers of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed applications, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handling and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address any warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

#### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Deminition of Terms		
Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev 177

<sup>\*</sup> Trademarks of System General Corporation, used under license by Fairchild Semiconductor.